Notice of Allowability	Application No.	Applicant(s)
	09/740,053	SHIRAKI ET AL.
	Examiner	Art Unit
	Christopher R. Magee	2653
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS I herewith (or previously mailed), a Notice of Allowance (PTOL-8: NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT of the Office or upon petition by the applicant. See 37 CFR 1.3:	S (OR REMAINS) CLOSED in t 5) or other appropriate commun RIGHTS. This application is su	his application. If not included ication will be mailed in due course. THIS
1. This communication is responsive to <u>11/10/2004</u> .		
2. The allowed claim(s) is/are 1-6,10,11 and 13-16 (renumb	pered 1-12, respectively).	
3. $\boxtimes$ The drawings filed on $\underline{5/17/2004}$ are accepted by the Exa	aminer.	÷
<ul> <li>4. Acknowledgment is made of a claim for foreign priority a)</li> <li>a) All b) Some* c) None of the:</li> <li>1. Certified copies of the priority documents had 2. Certified copies of the priority documents had 3. Copies of the certified copies of the priority documents had linear the priority documents had 3. Copies of the certified copies of the priority of linear linear (PCT Rule 17.2(a)).</li> <li>* Certified copies not received:</li> <li>Applicant has THREE MONTHS FROM THE "MAILING DATE noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.</li> </ul>	ve been received. ve been received in Application locuments have been received i	No In this national stage application from the
5. A SUBSTITUTE OATH OR DECLARATION must be sub INFORMAL PATENT APPLICATION (PTO-152) which gi	mitted. Note the attached EXAN ves reason(s) why the oath or d	MINER'S AMENDMENT or NOTICE OF leclaration is deficient.
6. ☐ CORRECTED DRAWINGS ( as "replacement sheets") m  (a) ☐ including changes required by the Notice of Draftspe  1) ☐ hereto or 2) ☐ to Paper No./Mail Date  (b) ☐ including changes required by the attached Examine Paper No./Mail Date  Identifying indicia such as the application number (see 37 CFR	rson's Patent Drawing Review ( r's Amendment / Comment or ir  1.84(c)) should be written on the	of the Office action of the Office in the front (not the back) of
each sheet. Replacement sheet(s) should be labeled as such in 7. DEPOSIT OF and/or INFORMATION about the depattached Examiner's comment regarding REQUIREMEN	osit of BIOLOGICAL MATER	RIAL must be submitted. Note the
Attachment(s)  1.  Notice of References Cited (PTO-892)  2.  Notice of Draftperson's Patent Drawing Review (PTO-948)  3.  Information Disclosure Statements (PTO-1449 or PTO/SB Paper No./Mail Date  4.  Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Sun Paper No./M /08), 7. ☐ Examiner's Al	rmal Patent Application (PTO-152) nmary (PTO-413), ail Date mendment/Comment tatement of Reasons for Allowance
Magre 116/04		

U.S. Patent and Trademark Office PTOL-37 (Rev. 1-04)

### **DETAILED ACTION**

## Response to Amendment

- 1. Applicant's request for reconsideration of the finality of the rejection of the last Office action is persuasive and, therefore, the finality of that action is withdrawn.
- 2. The reply filed 11/10/2004 was applied to the following effect: All relevant objections and rejections are withdrawn as being satisfied. Claim 12 has been cancelled.

## Reasons for Allowance

3. Claims 1-6, 10, 11, and 13-16 are allowed (renumbered as claims 1-12, respectively).

The following is an examiner's statement of reasons for allowance:

This application is for an INTEGRATED THIN FILM HEAD WITH MAGNETO-RESISTIVE SENSOR PREVENTING SHORT CIRCUIT BETWEEN THIN FILMS.

• Claims 1 and 4 specify an integrated thin film head, which requires:

"a thickness of a part of the lead layer in contact with upper lead layer is less than a thickness (a) of a part of the lead layer not in contact with the upper lead layer, and thickness (c) < (thickness (a) + thickness (b)), where thickness (c) is the total thickness of the lead layer and the upper lead layer where the position of the upper lead layer is in contact with the lead layer, and thickness (b) is the thickness of a portion of the upper lead layer not in contact with the lead layer."

The Applicant's Admitted Prior Art (AAPA) discloses thickness (c) = (thickness (a) + thickness (b)), where thickness (c) is the total thickness of the lead layer and the upper lead layer where the position of the upper lead layer is in contact with the lead layer, and thickness (b) is the thickness of a portion of the upper lead layer not in contact with the lead layer. The AAPA does not teach or suggest the applicant's invention as claimed.

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Shouji et al. (US 5,907,459) show the lower shield (48) being covered with the flat surface of the MR sensor layer (62) and lead layer (58) in a size smaller than the flat surface shape in the depth direction (col. 4, lines 10-26; Fig. 1).

Seagle (US 5,764,446) discloses a protective undercoat layer (320) formed on the substrate (100) comprising an insulative dielectric material such as alumina (col. 6, lines 33-36).

Therefore, these features, in combination with other features of claim 1 and 4, are not anticipated by, nor made obvious over, the closest prior art of record of the AAPA, Shouji '459 and/or Seagle '446.

# • Claim 13 specifies an integrated thin film head, which requires:

"wherein thickness (c) < (thickness (a) + thickness (b)), where thickness (a) is the thickness of the first part, thickness (b) is the thickness of a portion of the upper lead layer not in contact with the lead layer, and thickness (c) is the combined thickness of said portion of the upper lead layer overlapping said second part of said lead layer and said second part."

The Applicant's Admitted Prior Art (AAPA) discloses thickness (c) = (thickness (a) + thickness (b)), where thickness (c) is the total thickness of the lead layer and the upper lead layer where the position of the upper lead layer is in contact with the lead layer, and thickness (b) is the thickness of a portion of the upper lead layer not in contact with the lead layer. The AAPA does not teach or suggest the applicant's invention as claimed.

Shouji et al. (US 5,907,459) show the lower shield (48) being covered with the flat surface of the MR sensor layer (62) and lead layer (58) in a size smaller than the flat surface shape in the depth direction (col. 4, lines 10-26; Fig. 1).

Seagle (US 5,764,446) discloses a protective undercoat layer (320) formed on the substrate (100) comprising an insulative dielectric material such as alumina (col. 6, lines 33-36).

Therefore, these features, in combination with other features of claim 13, are not anticipated by, nor made obvious over, the closest prior art of record of the AAPA, Shouji '459 and/or Seagle '446.

4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

#### Conclusion

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Christopher R. Magee whose telephone number is (703) 605-4256. The examiner can normally be reached on M-F, 8: 00 am-5: 30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, William Korzuch can be reached on (703) 305-6137. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

December 6, 2004

Christopher R. Magee

Patent Examiner Art Unit 2653

A. J. HEINZ PRIMARY EXAMINER

GROUP # A. U. 2653